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Application/Control No.	Applicant(s)/Patent under Reexamination
09/675,992	LEE ET AL.
Examiner	Art Unit
Lena Najarian	3626

SEARCHED					
Class	Subclass	Date	Examiner		
709	203	7/6/2005	LN		
705	10 35 38	7/6/2005	LN		
· 706	21	7/6/2005	LN		
715	700	7/6/2005	LN		
705	26	7/7/2005	LN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	· EXMR
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/6/2005	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/7/2005	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/8/2005	LN
JSTOR (see attached printout)	7/8/2005	LN
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